


Search Notes 	Application/Control No. 09910206	Applicant(s)/Patent Under Reexamination BEUTEN ET AL.
	Examiner Ryan D. Coyer	Art Unit 2191

SEARCHED			
Class	Subclass	Date	Examiner
717	124,127-129	6/26/2007 and 1/21/08 and 1/13/09	SR
717	124-129	6/18/2009	RDC
714	30-39	6/18/2009	RDC

SEARCH NOTES		
Search Notes	Date	Examiner
East Updated	6/26/2007 and 1/21/08 and 1/13/09	SR
717/127-129 (text search--see the search history print out)	6/26/2007 and 1/21/08 and 1/13/09	SR
Wei Zhen, SPE (discussed the 101, 102, 103 rejections)	12/6/2006	SR
Wei Zhen, SPE (discusse the art and the amendment)	1/28/2008	SR
Text Search	1/21/2008 and 1/13/09	SR
PGPUB	1/21/2008 and 1/13/09	SR
EAST Search	6/18/2009	RDC
Inventor Name Search	6/18/2009	RDC
NPL Search - Google Scholar, IEEE, ACM; Keywords: memory swap, debug logic, thrashing, stack monitoring	6/18/2009	RDC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
717	124-129	6/19/2009	RDC

--	--